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Applications of RF/Microwave/Millimeter-Wave/THz Imaging

Guest Editor:

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Message from the Guest Editor

Sensing and imaging with electromagnetic waves have grown rapidly in the past few decades thanks to the significant progress in hardware components and processing algorithms. On the hardware side, the emergence of new and cost-effective sensors and their associated data acquisition boards has paved the way toward numerous novel applications. On the processing side, the development of faster computing machines has allowed for realization of more sophisticated algorithms that facilitate real-time or quasi real-time imaging and sensing of the media.

The objective of this Special Issue is to provide an overview of the current research on methods and applications of electromagnetic waves. Topics include but are not limited to:

- Hertz to tera-Hertz and beyond's imaging and its application
- electromagnetic waves in the imaging and sensing of media
- innovations and sensors in sensors
- data acquisition circuits
- sampling methods
- algorithms











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Message from the Editor-in-Chief

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